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PTO/SB/21 (03-03)

Approved for use through 04/30/2003. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

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<b>TRANSMITTAL FORM</b>  (to be used for all correspondence after initial filing)	Application Number	08/846,671
	Filing Date	April 30, 1997
	First Named Inventor	Kei-Yu Ko
	Art Unit	1763
	Examiner Name	George Goudreau
Total Number of Pages in This Submission	Attorney Docket Number	MI22-2041

ENCLOSURES (Check all that apply)		
<input checked="" type="checkbox"/> Fee Transmittal Form	<input type="checkbox"/> Drawing(s)	<input type="checkbox"/> After Allowance Communication to a Technology Center (TC)
<input checked="" type="checkbox"/> Fee Attached	<input type="checkbox"/> Licensing-related Papers	<input type="checkbox"/> Appeal Communication to Board of Appeals and Interferences
<input type="checkbox"/> Amendment/Reply	<input type="checkbox"/> Petition	<input type="checkbox"/> Appeal Communication to TC (Appeal Notice, Brief, Reply Brief)
<input type="checkbox"/> After Final	<input type="checkbox"/> Petition to Convert to a Provisional Application	<input type="checkbox"/> Proprietary Information
<input type="checkbox"/> Affidavits/declaration(s)	<input type="checkbox"/> Power of Attorney, Revocation	<input type="checkbox"/> Status Letter
<input type="checkbox"/> Extension of Time Request	<input type="checkbox"/> Change of Correspondence Address	<input checked="" type="checkbox"/> Other Enclosure(s) (please Identify below):
<input type="checkbox"/> Express Abandonment Request	<input type="checkbox"/> Terminal Disclaimer	Return Receipt Postcard; Certificate of Correction (2);
<input type="checkbox"/> Information Disclosure Statement	<input type="checkbox"/> Request for Refund	
<input type="checkbox"/> Certified Copy of Priority Document(s)	<input type="checkbox"/> CD, Number of CD(s) _____	
<input type="checkbox"/> Response to Missing Parts/Incomplete Application	Remarks	
<input type="checkbox"/> Response to Missing Parts under 37 CFR 1.52 or 1.53	Additional Enclosures: Request for Certificate of Correction; Copies of Initialed Forms PTO-1449; A \$100.00 Check.	
	Patent No. 6,849,557 B2 Issued: February 1, 2005	
<b>SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT</b>		
Firm or Individual	Mark S. Matkin, Reg. No. 32,268 Wells St. John, P.S.	
Signature		
Date	8/1/05	

Certificate  
AUG 15 2005

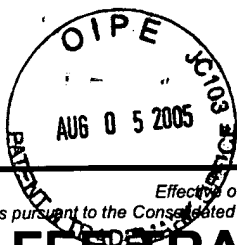
of Correction

CERTIFICATE OF TRANSMISSION/MAILING		
I hereby certify that this correspondence is being facsimile transmitted to the USPTO or deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, Washington, DC 20231 on this date: 8/2/05		
Typed or printed	Natalie King	
Signature		Date 8/2/05

This collection of information is required by 37 CFR 1.5. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 12 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

AUG 16 2005



Effective on 12/08/2004.  
Fees pursuant to the Consolidated Appropriations Act, 2005 (H.R. 4818).

# FEE TRANSMITTAL

## For FY 2005

☐ Applicant claims small entity status. See 37 CFR 1.27

TOTAL AMOUNT OF PAYMENT (\$) 100.00

### Complete if Known

Application Number	08/846,671
Filing Date	April 30, 1997
First Named Inventor	Kei-Yu Ko
Examiner Name	George Goudreau
Art Unit	1763
Attorney Docket No.	MI22-2041

### METHOD OF PAYMENT (check all that apply)

- ☒ Check ☐ Credit Card ☐ Money Order ☐ None ☐ Other (please identify): \_\_\_\_\_
- ☒ Deposit Account Deposit Account Number: 23-0925 Deposit Account Name: Wells St. John, P.S.
- For the above-identified deposit account, the Director is hereby authorized to: (check all that apply)
- ☐ Charge fee(s) indicated below ☐ Charge fee(s) indicated below, except for the filing fee
- ☒ Charge any additional fee(s) or underpayments of fee(s) under 37 CFR 1.16 and 1.17 ☒ Credit any overpayments

WARNING: Information on this form may become public. Credit card information should not be included on this form. Provide credit card information and authorization on PTO-2038.

### FEE CALCULATION

#### 1. BASIC FILING, SEARCH, AND EXAMINATION FEES

Application Type	FILING FEES		SEARCH FEES		EXAMINATION FEES		Fees Paid (\$)
	Fee (\$)	Small Entity Fee (\$)	Fee (\$)	Small Entity Fee (\$)	Fee (\$)	Small Entity Fee (\$)	
Utility	300	150	500	250	200	100	
Design	200	100	100	50	130	65	
Plant	200	100	300	150	160	80	
Reissue	300	150	500	250	600	300	
Provisional	200	100	0	0	0	0	

#### 2. EXCESS CLAIM FEES

##### Fee Description

Each claim over 20 (including Reissues)

Fee (\$)	Small Entity Fee (\$)
50	25

Each independent claim over 3 (including Reissues)

200	100
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Multiple dependent claims

360	180
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Total Claims	Extra Claims	Fee (\$)	Fee Paid (\$)
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\_\_\_\_\_ - 20 or HP = \_\_\_\_\_ x \_\_\_\_\_ = \_\_\_\_\_

HP = highest number of total claims paid for, if greater than 20.

Indep. Claims	Extra Claims	Fee (\$)	Fee Paid (\$)
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\_\_\_\_\_ - 3 or HP = \_\_\_\_\_ x \_\_\_\_\_ = \_\_\_\_\_

HP = highest number of independent claims paid for, if greater than 3.

#### 3. APPLICATION SIZE FEE

If the specification and drawings exceed 100 sheets of paper (excluding electronically filed sequence or computer listings under 37 CFR 1.52(e)), the application size fee due is \$250 (\$125 for small entity) for each additional 50 sheets or fraction thereof. See 35 U.S.C. 41(a)(1)(G) and 37 CFR 1.16(s).

Total Sheets	Extra Sheets	Number of each additional 50 or fraction thereof	Fee (\$)	Fee Paid (\$)
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\_\_\_\_\_ - 100 = \_\_\_\_\_ / 50 = \_\_\_\_\_ (round up to a whole number) x \_\_\_\_\_ = \_\_\_\_\_

#### 4. OTHER FEE(S)

Non-English Specification, \$130 fee (no small entity discount)

Fees Paid (\$)

Other (e.g., late filing surcharge): Request for Certificate of Correction

\$100.00

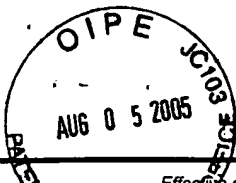
#### SUBMITTED BY

Signature	Registration No. 32,268	Telephone 509-624-4276
Name (Print Type) Mark S. Matkin	(Attorney/Agent)	Date 8/1/05

This collection of information is required by 37 CFR 1.136. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 30 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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AUG 16 2005



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First Named Inventor	Kei-Yu Ko
Examiner Name	George Goudreau
Art Unit	1763
Attorney Docket No.	MI22-2041

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Each independent claim over 3 (including Reissues)	200	100
Multiple dependent claims	360	180
<u>Total Claims</u>		
- 20 or HP = _____ x _____ = _____		
HP = highest number of total claims paid for, if greater than 20.		
<u>Indep. Claims</u>		
- 3 or HP = _____ x _____ = _____		
HP = highest number of independent claims paid for, if greater than 3.		
<u>Multiple Dependent Claims</u>		
Fee (\$)		
Fee Paid (\$)		

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<u>Total Sheets</u>	<u>Extra Sheets</u>	<u>Number of each additional 50 or fraction thereof</u>	<u>Fee (\$)</u>	<u>Fee Paid (\$)</u>
- 100 = _____	/ 50 = _____	(round up to a whole number) x _____	= _____	

#### 4. OTHER FEE(S)

Non-English Specification, \$130 fee (no small entity discount)	<u>Fees Paid (\$)</u>
Other (e.g., late filing surcharge): <u>Request for Certificate of Correction</u>	\$100.00

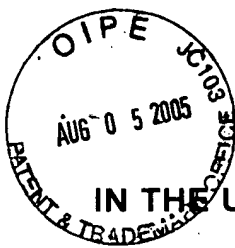
#### SUBMITTED BY

Signature <u>[Signature]</u>	Registration No. <u>32,268</u> (Attorney/Agent)	Telephone <u>509-624-4276</u>
Name (Print Type) <u>Mark S. Matkin</u>		Date <u>8/1/05</u>

This collection of information is required by 37 CFR 1.136. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 30 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.

AUG 16 2005



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent No..... 6,849,557 B1  
Patent Issue Date..... February 1, 2005  
Application Serial No..... 08/846,671  
Filing Date ..... April 30, 1997  
Assignee..... Micron Technology, Inc.  
Inventorship ..... Kei-Yu Ko  
Attorney's Docket No..... MI22-2041  
Title: Undoped Silicon Dioxide as Etch Stop for Selective Etch of Doped Silicon Dioxide

**REQUEST FOR CERTIFICATE OF CORRECTION OF PATENT FOR  
APPLICANT MISTAKES and PTO MISTAKES (37 C.F.R. §§ 1.322(a) and 1.323)**

To: Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450  
ATTN: Decision and Certificate of Correction  
Branch of the Patent Issue Division  
  
From: Mark S. Matkin (Tel. 509-624-4276; Fax 509-838-3424)  
Wells St. John P.S.  
601 W. First Avenue, Suite 1300  
Spokane, WA 99201-3828

Sir:

It is hereby requested that a Certificate of Correction be issued with respect to Patent No. 6,849,557 B1, granted February 1, 2005, in accordance with the Certificate of Correction form attached hereto in duplicate.

It is noted that errors appear in this patent of a typographical nature of character, as more fully described below. The errors occurred in good faith. Correction thereof does not involve such changes in the patent as would constitute new matter or would require re-examination.

Other errors listed on the Certificate of Correction form were apparently incurred through the fault of the PTO as will be disclosed by the records of files

08/08/2005 MWOLDGE1 00000022 6849557

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100.00 OP

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AUG 16 2005

in the Office. Regarding the references cited, copies of documents from the file are included herewith which evidence the Examiner's consideration and citation of the subject references.

Attached hereto, in duplicate, is Form PTO-1050, with at least one copy being suitable for printing.

The exact page and line number where the errors occur in the application file are:

Page 11, line 6;

Page 13, line 6;

Page 13, line 8;

Page 11, line 2, our claim 26 (PTO claim 21), of the Amendment filed March 7, 2003.

Enclosed is a check in the amount of \$100.00, as required by 37 CFR 1.20(a).

Respectfully submitted,

Dated: 8-1-05

By:



Mark S. Matkin  
Reg. No. 32,268

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 6,849,557 B1  
DATED : February 1, 2005  
INVENTOR(S) : Ko

It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

**Title Page 1, (56) References Cited, U.S. PATENT DOCUMENTS,**

4,672,740	06/1987	Shirai et al.
4,807,016	02/1989 *	Douglas
4,818,335	04/1989	Karnett
5,037,777	08/1991 *	Mele et al.
5,063,169	11/1991	DeBruin et al.

**Title Page 2, (56) References Cited, U.S. PATENT DOCUMENTS,**

5,192,703	03/1993	Lee et al.
5,208,176	05/1993	Ahmad et al.
5,210,047	05/1993	Woo et al.
5,229,311	07/1993	Lai et al.
5,269,879	12/1993	Rhoades et al.
5,298,465	03/1994	Levy
5,312,768	05/1994	Gonzalez
5,323,047	06/1994	Nguyen
5,393,704	02/1995	Huang et al.

Page  
1 of 6

**Mailing Address of Sender:**  
Mark S. Matkin  
Wells St. John P.S.  
601 West First Avenue, Suite 1300  
Spokane, WA 99201-3828

Patent No. 6,849,557 B1

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 6,849,557 B1  
DATED : February 1, 2005  
INVENTOR(S) : Ko

It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

5,403,779	04/1995	Joshi et al.
5,422,308	06/1995 *	Nicholls et al.
5,430,328	07/1995	Hsue
5,478,772	12/1995	Fazan
5,482,894	01/1996	Havemann
5,485,035	01/1996	Lin et al.
5,550,071	08/1996	Ryou
5,611,888	03/1997 *	Bosch et al.
5,658,425	08/1997	Halman et al.
5,685,914	11/1997	Hills et al.
5,705,427	01/1998	Chan et al.
5,731,242	03/1998	Parat et al.
5,747,369	05/1998 *	Kantimahanti et al.
5,780,338	07/1998	Jeng et al.
5,783,496	07/1998	Flanner
5,792,703	08/1998	Bonner et al.
5,817,579	10/1998	Ko et al.
5,821,594	10/1998 *	Kasai
5,830,807	11/1998	Matsunaga

Page  
2 of 6

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DATED : February 1, 2005  
INVENTOR(S) : Ko

It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

5,851,896	12/1998	Summerfelt
5,871,659	02/1999	Sakano et al.
5,908,320	06/1999	Chu et al.
5,946,568	08/1999	Hsiao et al.
6,065,481 A	05/2000	Fayfield et al.
6,074,488	06/2000	Roderick et al.
6,074,958	06/2000	Tokunaga et al.
6,117,788	09/2000	Ko
6,117,791	09/2000	Ko et al.
6,121,671	09/2000	Ko et al.
6,153,490	11/2000	Xing et al.
6,159,862	12/2000	Yamada et al.
6,165,880	12/2000	Yaung et al.
6,171,970 B1	01/2001	Xing et al.
6,174,451 B1	01/2001	Hung et al.
6,183,655 B1	02/2001	Wang et al.
6,254,966 B1	07/2001	Kondo
6,277,758 B1	08/2001	Ko
6,337,285 B1	01/2002	Ko

Page  
3 of 6

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PATENT NO. : 6,849,557 B1

DATED : February 1, 2005

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It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

6,362,109	03/2002	Kim et al.
6,372,605 B1	04/2002	Kuehne et al.
6,432,833 B1	08/2002	Ko
6,458,685 B1	10/2002	Ko et al.

Title Page 1, (56) **References Cited**, FOREIGN PATENT DOCUMENTS,

61-133,555	12/1984	Japan (Varta)
60-042,821	03/1985	* Japan (Sato)
0 496 614 A1	07/1992	EPO (NEC)
0 465 044 A2	08/1992	EPO (AT&T)
04-239,723	08/1992	Japan (Nakano)
6-69166	03/1994	Japan (Tokuhiko)
0 680 084 A1	04/1995	EPO (Texas Instruments)
8-181121	07/1996	Japan (Fujita)
8-250449	09/1996	Japan (Tetsuo)
0 763 850 A1	03/1997	EPO (Applied Materials)
WO 98/49719	11/1998	WIPO (Micron)

Page  
4 of 6

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Title Page 1, (56) **References Cited**, OTHER PUBLICATIONS,

Abatchev et al., *Study of the Boron-Phosphorous Doped and Undoped Silicate Glass Etching in CHF<sub>3</sub>/Ar Plasma*, 96 ELECTROCHEM. SOC. PROCEEDINGS, No. 12, pp. 522-530 (1996).

W.G.M. van den Hoek et al., *Isotropic plasma etching of doped and undoped silicon dioxide for contact holes and vias*, 7 J. VAC. SCI. TECHNOL. A., No. 3, pp. 670-675 (May/June 1989).

Serial No. 09/945,508; Filed 08/2001; Ko

Page  
5 of 6

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DATED : February 1, 2005  
INVENTOR(S) : Ko

It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Col. 3, line 12, please delete "s" after "undoped".

Col. 3, line 56, please delete "arc" after "stacks" and insert --are--.

Col. 5, line 23, please delete "in" after "28" and insert --is--.

Col. 6, line 33, please delete "enchants" after "fluorinated" and insert --etchants--.

Col. 6, line 40, please delete "enchant" before "is a" and insert --etchant--.

Col. 9, line 43, claim 21, please delete "contract" after "forming a" and insert --contact--.

Col. 12, line 5, claim 37, please insert --pressure-- after "at a".

Col. 13, line 41, claim 41, please delete "1millitorr" after "about" and insert --1 millitorr--.

Page  
6 of 6

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Patent No. 6,849,557 B1

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 6,849,557 B1  
DATED : February 1, 2005  
INVENTOR(S) : Ko

It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

5,851,896	12/1998	Summerfelt
5,871,659	02/1999	Sakano et al.
5,908,320	06/1999	Chu et al.
5,946,568	08/1999	Hsiao et al.
6,065,481 A	05/2000	Fayfield et al.
6,074,488	06/2000	Roderick et al.
6,074,958	06/2000	Tokunaga et al.
6,117,788	09/2000	Ko
6,117,791	09/2000	Ko et al.
6,121,671	09/2000	Ko et al.
6,153,490	11/2000	Xing et al.
6,159,862	12/2000	Yamada et al.
6,165,880	12/2000	Yaung et al.
6,171,970 B1	01/2001	Xing et al.
6,174,451 B1	01/2001	Hung et al.
6,183,655 B1	02/2001	Wang et al.
6,254,966 B1	07/2001	Kondo
6,277,758 B1	08/2001	Ko
6,337,285 B1	01/2002	Ko

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3 of 6

**Mailing Address of Sender:**  
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Wells St. John P.S.  
601 West First Avenue, Suite 1300  
Spokane, WA 99201-3828

Patent No. 6,849,557 B1

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PATENT NO. : 6,849,557 B1  
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It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

6,362,109	03/2002	Kim et al.
6,372,605 B1	04/2002	Kuehne et al.
6,432,833 B1	08/2002	Ko
6,458,685 B1	10/2002	Ko et al.

Title Page 1, (56) **References Cited**, FOREIGN PATENT DOCUMENTS,

61-133,555	12/1984		Japan (Varta)
60-042,821	03/1985	*	Japan (Sato)
0 496 614 A1	07/1992		EPO (NEC)
0 465 044 A2	08/1992		EPO (AT&T)
04-239,723	08/1992		Japan (Nakano)
6-69166	03/1994		Japan (Tokuhiko)
0 680 084 A1	04/1995		EPO (Texas Instruments)
8-181121	07/1996		Japan (Fujita)
8-250449	09/1996		Japan (Tetsuo)
0 763 850 A1	03/1997		EPO (Applied Materials)
WO 98/49719	11/1998		WIPO (Micron)

Page  
4 of 6

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Title Page 1, (56) **References Cited**, OTHER PUBLICATIONS,

Abatchev et al., *Study of the Boron-Phosphorous Doped and Undoped Silicate Glass Etching in CHF<sub>3</sub>/Ar Plasma*, 96 ELECTROCHEM. SOC. PROCEEDINGS, No. 12, pp. 522-530 (1996).

W.G.M. van den Hoek et al., *Isotropic plasma etching of doped and undoped silicon dioxide for contact holes and vias*, 7 J. VAC. SCI. TECHNOL. A., No. 3, pp. 670-675 (May/June 1989).

Serial No. 09/945,508; Filed 08/2001; Ko

Page  
5 of 6

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PATENT NO. : 6,849,557 B1

DATED : February 1, 2005

INVENTOR(S) : Ko

It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Col. 3, line 12, please delete "s" after "undoped".

Col. 3, line 56, please delete "arc" after "stacks" and insert --are--.

Col. 5, line 23, please delete "in" after "28" and insert --is--.

Col. 6, line 33, please delete "enchants" after "fluorinated" and insert --etchants--.

Col. 6, line 40, please delete "enchant" before "is a" and insert --etchant--.

Col. 9, line 43, claim 21, please delete "contract" after "forming a" and insert --contact--.

Col. 12, line 5, claim 37, please insert --pressure-- after "at a".

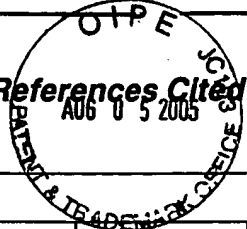
Col. 13, line 41, claim 41, please delete "1millitorr" after "about" and insert --1 millitorr--.

Page  
6 of 6

**Mailing Address of Sender:**

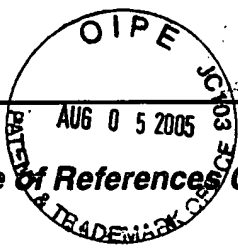
Mark S. Matkin  
Wells St. John P.S.  
601 West First Avenue, Suite 1300  
Spokane, WA 99201-3828

Patent No. 6,849,557 B1

<b>Notice of References Cited</b> 		Application No. <b>09-846,671</b>		Applicant(s) <b>Ko</b>	
		Examiner <b>George Goudreau</b>		Group Art Unit <b>1763</b>	
Page <b>1</b> of <b>1</b>					
<b>U.S. PATENT DOCUMENTS</b>					
*	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
A	<b>5,747,369</b>	<b>5-5-98</b>	<b>Kantimahanti et al</b>	<b>438</b>	<b>241</b>
B	<b>5,821,594</b>	<b>10-13-98</b>	<b>Kasal</b>	<b>257</b>	<b>410</b>
C	<b>5,637,777</b>	<b>8-6-91</b>	<b>Mele et al</b>	<b>437</b>	<b>195</b>
D	<b>5,422,308</b>	<b>6-6-95</b>	<b>Nicholls et al</b>	<b>437</b>	<b>192</b>
E					
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<b>FOREIGN PATENT DOCUMENTS</b>					
*	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS SUBCLASS
N					
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<b>NON-PATENT DOCUMENTS</b>					
*	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)				DATE
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V					
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\* A copy of this reference is not being furnished with this Office action.  
(See Manual of Patent Examining Procedure, Section 707.05(a).)





# Notice of References Cited

Application No.

08-846671

Applicant(s)

Ko

Examiner

George Goudreau

Group Art Unit

765

Page 1 of 1

## U.S. PATENT DOCUMENTS

*		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
A		4,807,016	2-21-89	Douglas	357	67
B		5,611,888	3-18-97	Bosch et al.	156	643
C						
D						
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G						
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M						

## FOREIGN PATENT DOCUMENTS

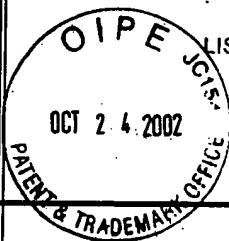
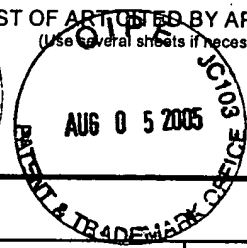
*		DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS
N		66-042,821	3-7-85	Japan	Sato et al.		
O		61-133,666	6-20-86	+	Yamazaki		
P							
Q							
R							
S							
T							

## NON-PATENT DOCUMENTS

*		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
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(See Manual of Patent Examining Procedure, Section 707.05(a).)

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCK. NO.  
MI22-2041SERIAL NO.  
08/846,671LIST OF ARTICLES BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yo Ko

FILING DATE  
April 30, 1997GROUP  
1763

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
gag	AA	5,269,879	12/14/93	Rhoades et al.	156	643	
	AB	5,298,465	03/29/94	Levy	437	225	
	AC	5,658,425	08/19/97	Halman et al.	438	620	
	AD	5,685,914	11/11/97	Hills et al.	118	723	
	AE	5,780,338	07/14/98	Jeng et al.	438	253	
	AF	5,783,496	07/21/98	Flanner et al.	438	743	
	AG	5,817,579	10/06/98	Ko et al.	438	740	
	AH	5,830,807	11/03/98	Matsunaga et al.	438	714	
	AI	5,908,320	06/01/99	Chu et al.	438	43	
gag	AJ	5,946,568	08/31/99	Hsiao et al.	438	253	

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Registration
gag	AK	JP 61133555	12.09.86	Japan (Varta Batterie)			Abstract
	AL	0-680-084-A1	28.04.95	EPO (Texas Instruments Inc.)			
gag	AM	WO 98/89719	05.11.98	WIPO (Micron Technology, Inc.)			

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

gag	AN	Abatchev et al., Study of the Boron-Phosphorous Doped and Undoped Silicate Glass Etching in CHF <sub>3</sub> /Ar Plasma, 96 ELECTROCHEM. SOC. PROCEEDINGS, No. 12, pp. 522-530 (1996). ✓
	AO	
	AP	

EXAMINER

George Goudreau

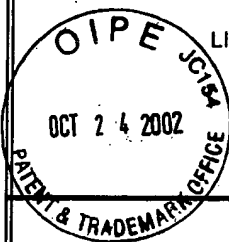
DATE CONSIDERED

12-021

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2041SERIAL NO.  
08/846,671LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yo Ko

FILING DATE  
April 30, 1997GROUP  
1763

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OCT 30 2002  
TC 1700

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
gry	AA	5,871,659 ✓	02/16/99	Sakano et al.	216	79	_____
	AB	5,883,436 ✓	03/16/99	Sadjadi et al.	257	760	_____
	AC	6,074,488 ✓	06/13/00	Roderick et al.	118	728	_____
	AD	6,074,958 ✓	06/13/00	Tokunaga et al.	438	724	_____
	AE	6,117,788 ✓	09/12/00	Ko	438	706	_____
	AF	6,117,791 ✓	09/12/00	Ko et al.	438	723	_____
	AG	6,121,671 ✓	09/19/00	Ko et al.	257	644	_____
	AH	6,153,490 ✓	11/28/00	Xing et al.	438	396	_____
	AI	6,159,862 ✓	12/12/00	Yamada et al.	438	712	_____
gry	AJ	6,165,880 ✓	12/26/00	Yaung et al.	438	592	_____

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AK							
	AL							
	AM							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AN		
	AO		
	AP		

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George Goudreau

DATE CONSIDERED

12-021

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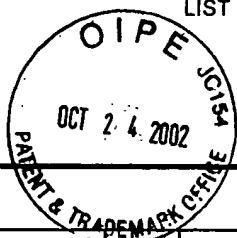
AUG 16 2005

AUG 16 2005

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOKL. NO.  
MI22-2041SERIAL NO.  
08/846,671LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yo Ko

FILING DATE  
April 30, 1997GROUP  
1763

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
gag	AA 6,171,970 B1	01/09/01	Xing et al.	438	706	
	AB 6,174,451 B1	01/16/01	Hung et al.	216	67	
	AC 6,183,655 B1	02/06/01	Wang et al.	216	68	
	AD 6,254,966 B1	07/03/01	Kondo	428	156	
	AE 6,337,285 B1	01/08/02	Ko	438	714	
	AF 6,432,833 B1	08/13/02	Ko	438	714	
gag	AG 6,458,685 B2	10/01/02	Ko et al.	438	621	
	AH <del>09/532,088</del>	<del>03/21/2000</del>	<del>Ko (as amended)</del>			<del>03/21/2000</del>
	AI <del>09/045,508</del>	<del>08/30/2001</del>	<del>Ko (as filed and as amended)</del>			<del>08/30/2001</del>
	AJ					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AK						
	AL						
	AM						

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

gag	AN	09/532,088; (Ko); 3-21-00
gag	AO	09/945,508 (Ko); 8-30-01
	AP	

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OCT 30 2002  
TC 1700





Applicant: Kei-Yu Ko  
Serial No.: 08/846,671  
Filing Date: April 30, 1998  
For: UNDOPE

UNDOPED SILICON DIOXIDE AS ETCH STOP FOR SELECTIVE  
ETCH OF DOPED SILICON DIOXIDE

at'y Docket No.: 11675.114  
Group: 1763

SUPPLEMENTAL INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANT

U.S. Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Issue <u>Date</u>	<u>Name</u>	<u>Class</u>	<u>Sub Class</u>
1	6,277,758 B1 ✓	08/21/01	Ko	438	706

## Foreign Patent Documents

Examiner Initial*	Document Number	Publ. Date	Country or Patent Office	<del>Class</del> Class	<del>Class</del> Class	<del>Class</del> Class
gpg	2 0 496 614 A1 ✓	07/29/92	EPO	<del>NO 12 21</del>	3105	yes
	3 0 465 044 A2 ✓	08/01/92	EPO	<del>NO 12 21</del>	90	
gpg	4 0 763 850 A1 ✓	03/19/97	EPO	<del>NO 12 21</del>	314	

COPY  
ORIGINAL

## Other Documents

(including author, title, pertinent pages, etc.)

Examiner  
Initial\*

5 Van den Hoek et al., *Isotropic Plasma Etching of Doped and Undoped Silicon Dioxide for Contact Holes and Vias*, J. Vac. Sci. Technol. A, Vol. 7, No. 3, pp. 670-675, 1989.

### References Cited by Applicants

While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

Examiners will consider all citations submitted in conformance with 37 C.F.R. § 1.98 and MPEP Sec. 609 and place their initials adjacent the citations in the spaces provided on this form. Examiners will also initial citations not in conformance with the guidelines which may have been considered. A reference may be considered by the Examiner for any reason whether or not the citation is in full conformance with the guidelines. A line will be drawn through a citation if it is not in conformance with the guidelines AND has not been considered. A copy of the submitted form, as reviewed by the Examiner, will be returned to the applicant with the next communication. The original of the form will be entered into the application file.

Each citation initiated by the Examiner will be printed on the issued patent in the same manner as references cited by the Examiner on Form PTO-892.

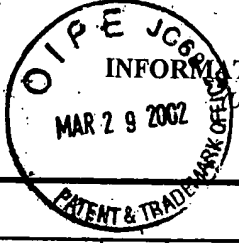
The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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Examiner:

Date Considered:

AUG 16 2005



## INFORMATION DISCLOSURE CATION

(Use several sheets if necessary)

Docket Number (Optional)

11675.114

Application Number

08/846,671

Applicant(s)

Ko

Filing Date

April 30, 1997

Group Art Unit

1763

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
gag	1.	5,192,703 ✓	3/93	Lee et al	438	396	
	2.	5,792,703 ✓	8/98	Bonner et al	438	620	
	3.	5,478,772 ✓	12/95	Fazen	148	DIG.14	
	4.	5,312,768 ✓	5/94	Gonzalez	438	227	
	5.	5,550,071 ✓	8/96	Ryou	438	305	
	6.	5,731,242 ✓	3/98	Parat et al	438	211	
	7.	5,208,176 ✓	5/93	Ahmad et al	257	499	
	8.	5,210,047 ✓	5/93	Woo et al	148	DIG.19	
	9.	5,482,894 ✓	1/96	Havemann	438	623	
gag	10.	5,063,169 ✓	11/91	De Bruin et al	148	DIG.26	

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

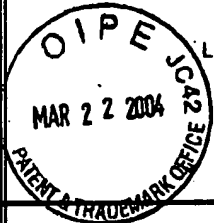
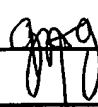

EXAMINER

George Gouldreau

DATE CONSIDERED

9-021

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2041		SERIAL NO. 08/846,671	
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>					APPLICANT: Kei-Yu Ko			
					FILING DATE April 30, 1997		GROUP 1763	
<b>U.S. PATENT DOCUMENTS</b>								
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	4,672,740	06/16/87	Shirai et al.				
	AB	5,229,311	07/20/93	Lai et al.				
	AC	5,393,704	02/28/95	Huang et al.				
	AD	5,705,427	01/06/98	Chan et al.				
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<b>FOREIGN PATENT DOCUMENTS</b>								
		Document Number	Date	Country	Class	Subclass	Translation	
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	AL							
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
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	AN							
	AO							
EXAMINER		DATE CONSIDERED						
George Goudreau		8-04'						
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2041		SERIAL NO. 08/846,671	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) <div style="position: absolute; top: 50px; left: 50px; border: 2px solid black; border-radius: 50%; padding: 10px; text-align: center;">             OFFICE              JUL 26 2004              PATENT &amp; TRADEMARK OFFICE           </div>				APPLICANT: Kei-Yu Ko			
				FILING DATE April 30, 1997		GROUP 1763	

U.S. PATENT DOCUMENTS							
Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
gag	AA	5,403,779	04/1995	Joshi et al.	438	634	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
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AI							
AJ							
AK							
AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
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EXAMINER <i>George Goudreau</i>	DATE CONSIDERED <i>8-04'</i>
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Sheet 1 of 1

Form PTO-449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2041	SERIAL NO. 08/846,671
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Kei-Yu Ko	
				FILING DATE April 30, 1997	GROUP 1763

U.S. PATENT DOCUMENTS							
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
GAY	AA	5,430,328	07/04/95	Hsue			
	AB	6,065,481	05/23/00	Fayfield et al.			
	AC	6,362,109	03/26/02	Kim et al.			
GAY	AD	6,372,605 B1	04/16/02	Kuehne et al.			
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS							
Examiner's Initials	Class	Document Number	Date	Country	CST	PCT	Filing Date if Appropriate
GAY	AI	84-239723	27.08.92	Japan (Nakano)			
	AJ	6-69166	11.03.94	Japan (Tokuhiko)			
	AK	8-181121	12.07.95	Japan (Fujita)			
GAY	AL	8-250449	27.09.96	Japan (Tetsuo)			

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AM		
	AM		
	AO		

EXAMINER: George Goudreau	DATE CONSIDERED 8-04-97
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.